

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYAKE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0220531 A1	11-2003	Cortright et al.	585/733
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2002-015746	01-2002	Japan	Yonezu et al.	H01M 4/96
	O	WO 02/13295 A1	02-2002	PCT	Nokuma et al.	H01M 4/86
	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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